

RELIABILITY MONITOR

DS1000Z-25 OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1000	E3	0033	DE009456ACE	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 1.2 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26046	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
26047	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	76	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.04E+07		0
26048	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			37	1000	CYCL	0
		TOTAL:				0
26049	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
26050	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	38	96	HOUR	0
		TOTAL:				0

PROJECT NO: 15226

RELIABILITY MONITOR

DS1232L OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0039	DE028679ADB 8	SOIC	150x1.4	OSEP	
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26089	INFANT LIFE	125C, 7.0 VOLTS	232	48	HOUR	0
26090	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.08E+07		0
26086	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26087	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
26088	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26091	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
26092	HAST	130C, 85%R.H.,5.5V	76	100	HOUR	0
		TOTAL:				0
26093	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	39	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16486

RELIABILITY MONITOR

DS1232L OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0039	DE028679ADB	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μ m Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
--------	----------	-----------	----------	-----------	-------	-------------

RELIABILITY MONITOR

DS1232L JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1232	C2-L	0051	DK038265AAC	8	SOIC	150x1.4	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26435	INFANT LIFE	125C, 7.0 VOLTS	233	48	HOUR	0
26436	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			235	FAIL RATE (Fits): DEVICE HRS: 3.91E+06		0
26433	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0

PROJECT NO: 16721

RELIABILITY MONITOR

DS1233Z-10 JUL '00 Monitor

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0025	DM009468AAA 3	SOT223	140x1.7	Carsem	
PROCESS Single Poly, Single Metal 1.2 µm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25800	INFANT LIFE	125C, 7.0 VOLTS	221	48	HOUR	0
25801	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	75	336	HOUR	0
		125C, 7.0 VOLTS	68	1000	HOUR	1
TOTAL:			72	DEVICE HRS: 2.80E+07		1
25798	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235C	233	3	PASS	0
TOTAL:						0
25802	TEMP CYCLE	-55C TO 125C	37	700	CYCL	0
			36	1000	CYCL	2
TOTAL:						2
25803	HAST	130C, 85%R.H.,5.5V	72	100	HOUR	1
TOTAL:						1
25804	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
25801	VCC TRIPPT	VERIFICATION IN PROCESS	NA			
25802	ICC STANDBY	VERIFICATION IN PROCESS	NA			

PROJECT NO: 16200

RELIABILITY MONITOR

DS1233Z-10 JUL '00 Monitor

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0025	DM009468AAA	3	SOT223	140x1.7	Carsem
PROCESS Single Poly, Single Metal 1.2 μ m Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25803	PB TRIPPT	VERIFICATION IN PROCESS				NA

PROJECT NO: 16200

RELIABILITY MONITOR

DS1233Z-10 OCT '00 Monitor

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0038	DA017172ABA	3	SOT223	140x1.7	Fastech
PROCESS Single Poly, Single Metal 1.2 µm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26126	INFANT LIFE	125C, 7.0 VOLTS	225	48	HOUR	0
26127	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	68	336	HOUR	0
		125C, 7.0 VOLTS	68	1000	HOUR	0
TOTAL:			33	DEVICE HRS: 2.75E+07		0
26124	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235C	233	3	PASS	3
TOTAL:						3
26128	TEMP CYCLE	-55C TO 125C	40	700	CYCL	1
			39	1000	CYCL	6
TOTAL:						7
26129	HAST	130C, 85%R.H.,5.5V	75	100	HOUR	0
TOTAL:						0
26130	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
26124	VARIOUS	REJECT MIXING.	SEE CA #752.			
26128	VARIOUS	REJECT MIXING.	SEE CA #752.			

PROJECT NO: 16488

RELIABILITY MONITOR

DS1233Z-10 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1233	A5	0049	DA033011ABA	3	SOT223	140x1.7	Fastech
PROCESS Single Poly, Single Metal 1.2 μm Zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26443	INFANT LIFE	125C, 7.0 VOLTS	225	48	HOUR	0
26444	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	68	336	HOUR	0
TOTAL:			78	DEVICE HRS: 1.18E+07		0
26441	STORAGE LIFE	125C	233	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	233	168	HOUR	
	CONVECTION REFLOW	235C	233	3	PASS	0
TOTAL:						0
26445	TEMP CYCLE	-55C TO 125C	40	700	CYCL	0
TOTAL:						0
26446	HAST	130C, 85%R.H.,5.5V	72	100	HOUR	0
TOTAL:						0
26447	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
TOTAL:						0

PROJECT NO: 16722

RELIABILITY MONITOR

DS1267-100 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A2	9930	DK904472ADF	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 µm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25175	INFANT LIFE	125C, 6.0 V, -4.0V	226	48	HOUR	0
25176	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	77	1000	HOUR	13
TOTAL:			1437	FAIL RATE (Fits): DEVICE HRS: 1.02E+07		13
25172	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25173	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25174	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25177	TEMP CYCLE	-55C TO 125C	36	300	CYCL	0
			36	1000	CYCL	0
TOTAL:						0
25178	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
TOTAL:						0
25179	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	36	96	HOUR	0

PROJECT NO: 14260

RELIABILITY MONITOR

DS1267-100 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A2	9930	DK904472ADF	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
25176	256BRKDNV (13)	IN VERIFICATION	NA			

RELIABILITY MONITOR

DS1267-010 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0021	DK012170AAA	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25834	INFANT LIFE	125C, 6.0 V, -4.0V	224	48	HOUR	0
25835	HIGH VOLTAGE LIFE	125C, 6.0 V, -4.0V	77	336	HOUR	0
		125C, 6.0 V, -4.0V	73	1000	HOUR	0
		TOTAL:	85	DEVICE HRS: 1.08E+07		0
25831	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25832	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25833	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25836	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
			35	1000	CYCL	0
		TOTAL:				0
25837	BIASED MOISTURE	85/85, 5.5 VOLTS	75	274	HOUR	0
			69	959	HOUR	0
		TOTAL:				0
25838	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	35	96	HOUR	0

PROJECT NO: 16218

RELIABILITY MONITOR

DS1267-010 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0021	DK012170AAA	20	TSSOP	4.4x0.9	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 1.2 μ m Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

RELIABILITY MONITOR

DS1267-010 FEB '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1267	A1	0102	DM039441ABC	20	TSSOP	4.4x0.9	Carsem S
PROCESS Single Poly, Single Metal 1.2 μm Implanted Poly 1							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26571	INFANT LIFE	125C, 6.0 V, -4.0V	234	48	HOUR	0
TOTAL:			635	DEVICE HRS: 1.44E+06		0
26569	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0

PROJECT NO: 17061

RELIABILITY MONITOR

DS1302 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	0032	DH020619AAA	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25931	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
25932	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
		TOTAL:	82	DEVICE HRS: 1.12E+07		0
25933	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
25934	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
25935	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	38	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16360

RELIABILITY MONITOR

DS1302 DEC '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1302	A3	0032	DH028629ABD	8	PDIP	300	CPS (ChipPac, China)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26332	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26333	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			192	DEVICE HRS: 4.77E+06		0
26334	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
26335	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0
26336	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

PROJECT NO: 16631

RELIABILITY MONITOR

DS1621 MAR '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9950	DE940040AAC	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25220	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
25221	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.09E+07		0
25217	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25218	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
		TOTAL:				0
25219	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25222	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
25223	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	0
			69	959	HOUR	0
		TOTAL:				0
25224	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	50	50	KCYC	0

PROJECT NO: 13948

RELIABILITY MONITOR

DS1621 MAR '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1621	A7	9950	DE940040AAC	8	SOIC	150x1.4	OSEP
PROCESS Single Poly, Single Metal 0.8 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0
25225	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0

PROJECT NO: 13948

RELIABILITY MONITOR

DS1803-010 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9923	DK913631AAA	16	SOIC	150x1.4	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
24738	INFANT LIFE	125C, 7.0 VOLTS	224	48	HOUR	0
24739	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.07E+07		0
24735	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
24736	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
24737	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
24740	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
24741	BIASED MOISTURE	85/85, 5.5 VOLTS	67	274	HOUR	0
			67	959	HOUR	0
		TOTAL:				0
24742	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0

PROJECT NO: 13967

RELIABILITY MONITOR

DS1803-010 NOV '99 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	9923	DK913631AAA	16	SOIC	150x1.4	ATP (Anam, PI)
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

PROJECT NO: 13967

RELIABILITY MONITOR

DS1803-010 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0007	DE946274AAA	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25191	INFANT LIFE	125C, 7.0 VOLTS	226	48	HOUR	0
25192	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	75	336	HOUR	0
		125C, 7.0 VOLTS	62	1000	HOUR	0
		TOTAL:	38	DEVICE HRS: 2.43E+07		0
25188	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25189	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25190	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25193	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
		TOTAL:				0
25194	BIASED MOISTURE	85/85, 5.5 VOLTS	68	274	HOUR	0
			57	959	HOUR	0
		TOTAL:				0
25195	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	35	96	HOUR	0
		TOTAL:				0

PROJECT NO: 14167

RELIABILITY MONITOR

DS1803-010 FEB '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0007	DE946274AAA	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
--------	----------	-----------	----------	-----------	-------	-------------

PROJECT NO: 14167

RELIABILITY MONITOR

DS1803-010 MAY '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0013	DE951193AAF	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25438	INFANT LIFE	125C, 7.0 VOLTS	227	48	HOUR	0
25439	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	0
		125C, 7.0 VOLTS	65	1000	HOUR	0
		TOTAL:	35	DEVICE HRS: 2.59E+07		0
25435	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25436	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25437	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25440	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
			20	1000	CYCL	0
		TOTAL:				0
25441	BIASED MOISTURE	85/85, 5.5 VOLTS	64	274	HOUR	0
		TOTAL:				0
25442	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	35	96	HOUR	0
		TOTAL:				0

PROJECT NO: 15292

RELIABILITY MONITOR

DS1803-010 MAY '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0013	DE951193AAF	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
--------	----------	-----------	----------	-----------	-------	-------------

RELIABILITY MONITOR

DS1803-010 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1803	A2	0034	DE023435AAB	16	SOIC	150x1.4	OSEP
PROCESS Single Poly, Double Metal 0.8 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25925	INFANT LIFE	125C, 7.0 VOLTS	221	48	HOUR	0
25926	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			73	DEVICE HRS: 1.25E+07		0
25922	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25923	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
25924	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25927	TEMP CYCLE	-55C TO 125C	35	300	CYCL	0
TOTAL:						0
25928	BIASED MOISTURE	85/85, 5.5 VOLTS	64	274	HOUR	0
TOTAL:						0
25929	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	30	96	HOUR	0
TOTAL:						0

PROJECT NO: 16359

RELIABILITY MONITOR

DS1869 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	0017	DH833210AAB	8	SOIC	208x1.9	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 1.2 μm E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: Tuse:
Ea: Vuse:
β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25543	INFANT LIFE	125C, 7.0 VOLTS	236	48	HOUR	0
25544	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	76	336	HOUR	1
TOTAL:			159	DEVICE HRS: 1.27E+07		1
25540	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25541	STORAGE LIFE	125C	241	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	241	168	HOUR	
	CONVECTION REFLOW	235C	241	3	PASS	0
TOTAL:						0
25542	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25545	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
25546	BIASED MOISTURE	85/85, 5.5 VOLTS	70	274	HOUR	1
TOTAL:						1
25547	WRITE CYCLE STRESS	85 C, 7.0 VOLTS	48	25	KCYC	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
25544	ICC STANDBY	VERIFICATION IN PROCESS	NA

PROJECT NO: 14164

RELIABILITY MONITOR

DS1869 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS1869	A3	0017	DH833210AAB	8	SOIC	208x1.9	CPS (ChipPac, China
PROCESS Single Poly, Single Metal 1.2 μ m E2PROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	60%	Tuse:	55 °C
Ea:	0.7	Vuse:	5.5 Volts
β :	1		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25546	ICC STANDBY	VERIFICATION IN PROCESS				NA

RELIABILITY MONITOR

DS2108 MAY '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0019	DK007198AAF	24	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25525	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
25526	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	82	DEVICE HRS: 1.12E+07		0
25522	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25523	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	3
		TOTAL:				3
25524	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25527	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
25528	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			76	959	HOUR	0
		TOTAL:				0
25529	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0

PROJECT NO: 14171

RELIABILITY MONITOR

DS2108 MAY '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0019	DK007198AAF	24	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
25523	R BOT 1	IN PROCESS	NA			

PROJECT NO: 14171

RELIABILITY MONITOR

DS2108 AUG '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0029	DK016058AAG	24	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25857	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
25858	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
		TOTAL:	83	DEVICE HRS: 1.11E+07		0
25854	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25855	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25856	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25859	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
25860	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	3
			74	959	HOUR	0
		TOTAL:				3
25861	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	33	96	HOUR	0

PROJECT NO: 16238

RELIABILITY MONITOR

DS2108 AUG '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0029	DK016058AAG	24	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
25860	FAUSE	IN PROCESS	NA			

PROJECT NO: 16238

RELIABILITY MONITOR

DS2108 FEB '01 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2108	B7	0051	DN041061AAE	24	SOIC	300x2.3	ATK (Anam, K)
PROCESS Single Poly, Single Metal 5.0 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26579	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26580	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			638	FAIL RATE (Fits): DEVICE HRS: 1.44E+06		0
26577	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	144	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26581	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
26582	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0

PROJECT NO: 17081

RELIABILITY MONITOR

DS2118M SEP '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0033	DN020718AAD	36	SSOP	7.5x2.4	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25943	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
25944	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
		TOTAL:	82	FAIL RATE (Fits): DEVICE HRS: 1.12E+07		0
25940	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25941	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25942	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25945	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
			77	1000	CYCL	0
		TOTAL:				0
25946	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	77	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16261

RELIABILITY MONITOR

DS2118M DEC '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2118M	B1	0047	DN033148ACE	36	SSOP	7.5x2.4	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Negative zero tempco poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26362	INFANT LIFE	125C, 6.0 VOLTS	233	48	HOUR	7
26363	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
TOTAL:			740	DEVICE HRS: 1.13E+07		7
26360	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26364	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
			70	1000	CYCL	0
TOTAL:						0
26365	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	77	96	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
26362	RSE SE	GATE OXIDE.	SEVERAL EVALUATIONS ARE IN PROCESS TO IMPROVE GATE OXIDE PERFORMANCE

PROJECT NO: 16632

RELIABILITY MONITOR

DS21352 DEC '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21352	A4	0044	DK031452ABB	100	LQFP	14x14x	ATP (Anam, PI)
PROCESS Double Poly, Double Met 0.6 µm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26355	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
26356	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			194	FAIL RATE (Fits): DEVICE HRS: 4.72E+06		0
26352	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26353	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	3
TOTAL:						3
26357	TEMP CYCLE	-55C TO 125C	77	300	CYCL	0
TOTAL:						0
26358	HAST, NO BIAS	130C, 85% R.H.	71	200	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
26353	JIT TOL	VERIFICATION IN PROCESS				

PROJECT NO: 16635

RELIABILITY MONITOR

DS2154 SEP '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0034	DK022283AAA	100	LQFP	14x14x	ATP (Anam, PI)
PROCESS Double Poly, Double Met 0.8 μm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25958	INFANT LIFE	125C, 7.0 VOLTS	191	48	HOUR	0
25959	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	60	336	HOUR	0
		125C, 7.0 VOLTS	60	1000	HOUR	0
		TOTAL:	38	FAIL RATE (Fits): DEVICE HRS: 2.39E+07		0
25955	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25956	STORAGE LIFE	125C	238	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	0
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25957	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25960	TEMP CYCLE	-55C TO 125C	63	300	CYCL	0
			63	1000	CYCL	0
		TOTAL:				0
25961	HAST, NO BIAS	130C, 85% R.H.	64	200	HOUR	0
		TOTAL:				0

PROJECT NO: 16371

RELIABILITY MONITOR

DS2154 DEC '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2154	A2	0036	DC022275AAB	100	LQFP	14x14x	Stats
PROCESS Double Poly, Double Met 0.8 µm Capacitor							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26377	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	2
26378	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			252	DEVICE HRS: 1.23E+07		2
26374	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26375	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	238	240	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0
26379	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
			70	1000	CYCL	0
TOTAL:						0
26380	HAST, NO BIAS	130C, 85% R.H.	77	200	HOUR	0
TOTAL:						0
JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION			
26378	JIT TOL (2)	VERIFICATION IN PROCESS				

PROJECT NO: 16634

RELIABILITY MONITOR

DS2175 OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0042	DK031506AAC	16	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26108	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
26109	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	
		TOTAL:	71	FAIL RATE (Fits):		0
				DEVICE HRS: 1.30E+07		
26106	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
26107	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26110	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
		TOTAL:				0
26111	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
26112	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16495

RELIABILITY MONITOR

DS2175 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2175	D1	0046	DE033119AAB	16	SOIC	300x2.3	ATP (Anam, PI)
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26422	INFANT LIFE	125C, 7.0 VOLTS	233	48	HOUR	
TOTAL:			FAIL RATE (Fits):		DEVICE HRS:	
26420	TEMP CYCLE	-55C TO 125C	238	10	CYCL	
	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
TOTAL:						0

PROJECT NO: 16724

RELIABILITY MONITOR

DS2181A JUL '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2181A	A2	0016	DE004552ABD	44	PLCC	650x65	OSEP
PROCESS Single Poly, Single Metal 2.0 µm Pfield							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25818	INFANT LIFE	125C, 7.0 VOLTS	237	48	HOUR	0
25819	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			70	FAIL RATE (Fits): DEVICE HRS: 1.30E+07		0
25815	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
25816	TEMP CYCLE	-55C TO 125C	241	10	CYCL	0
	STORAGE LIFE	125C	241	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	241	144	HOUR	0
	VAPOR PHASE REFLOW	217C	241	3	PASS	0
TOTAL:						0
25817	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0
25820	TEMP CYCLE	-55C TO 125C	60	300	CYCL	0
TOTAL:						0
25821	HAST	130C, 85%R.H.,5.5V	59	100	HOUR	0
TOTAL:						0
25822	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

PROJECT NO: 14022

RELIABILITY MONITOR

DS2181A JUL '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2181A	A2	0016	DE004552ABD	44	PLCC	650x65	OSEP
PROCESS Single Poly, Single Metal 2.0 μm Pfield							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
--------	----------	-----------	----------	-----------	-------	-------------

RELIABILITY MONITOR

DS21Q43A JUN '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0014	DN004571AAB	128	LQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25504	INFANT LIFE	125C, 6.0 VOLTS	224	48	HOUR	0
25505	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	75	1000	HOUR	0
		TOTAL:	85	DEVICE HRS: 1.08E+07		0
25501	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25502	STORAGE LIFE	125C	239	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	0
	CONVECTION REFLOW	235C	239	3	PASS	0
		TOTAL:				0
25503	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25506	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
			69	1000	CYCL	0
		TOTAL:				0
25507	BIASED MOISTURE	85/85, 5.5 VOLTS	39	274	HOUR	0
			36	959	HOUR	0
		TOTAL:				0
25508	HAST, NO BIAS	130C, 85% R.H.	38	100	HOUR	0

PROJECT NO: 14281

RELIABILITY MONITOR

DS21Q43A JUN '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0014	DN004571AAB	128	LQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

RELIABILITY MONITOR

DS21Q43A SEP '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS PACKAGE	WIDTH ASSEMBLY SITE
DS21Q43	A3-A	0031	DC022318AAD	128 LQFP	14x20x Stats
PROCESS Single Poly, Single Metal 0.6 μm Standard Process					

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25950	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
25951	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	75	1000	HOUR	0
		TOTAL:	84	DEVICE HRS: 1.09E+07		0
25947	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25948	STORAGE LIFE	125C	239	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	0
	CONVECTION REFLOW	235C	239	3	PASS	0
		TOTAL:				0
25949	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25952	TEMP CYCLE	-55C TO 125C	70	300	CYCL	0
			70	1000	CYCL	0
		TOTAL:				0
25953	BIASED MOISTURE	85/85, 5.5 VOLTS	46	274	HOUR	0
			42	959	HOUR	0
		TOTAL:				0
25954	HAST, NO BIAS	130C, 85% R.H.	36	100	HOUR	0

PROJECT NO: 16370

RELIABILITY MONITOR

DS21Q43A SEP '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0031	DC022318AAD	128	LQFP	14x20x	Stats
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
TOTAL:						0

RELIABILITY MONITOR

DS21Q43A DEC '00 MONITOR, D.P.

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS21Q43	A3-A	0034	DN027568AAC	128	LQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26369	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26370	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	76	336	HOUR	0
TOTAL:			635	FAIL RATE (Fits): DEVICE HRS: 1.44E+06		0
26366	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26367	STORAGE LIFE	125C	239	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	0
	CONVECTION REFLOW	235C	239	3	PASS	0
TOTAL:						0
26372	BIASED MOISTURE	85/85, 5.5 VOLTS	31	274	HOUR	0
TOTAL:						0

PROJECT NO: 16633

RELIABILITY MONITOR

DS2401 DEC '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2401	C2	0035	DM014457ADA	3	TO92	150	Fastech
PROCESS Single Poly, Single Metal 0.6 μm Standard Process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26337	INFANT LIFE	125C, 6.0 VOLTS	234	48	HOUR	0
26338	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	DEVICE HRS: 1.13E+07		0
26339	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			39	1000	CYCL	0
		TOTAL:				0
26340	HAST	130C, 85%R.H.,5.5V	77	100	HOUR	0
		TOTAL:				0
26341	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	40	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16637

RELIABILITY MONITOR

DS2502 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C3	0011	DM941230AGB 8	8	SOIC	150x1.4	Carsem S
PROCESS Double Poly, Single Metal 0.6 μm EPROM process							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25568	INFANT LIFE	125C, 6.0 VOLTS	231	48	HOUR	0
25569	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	81	DEVICE HRS: 1.13E+07		0
25565	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25566	STORAGE LIFE	125C	238	24	HOUR	
	MOISTURE SOAK	85C/85% R.H.	238	168	HOUR	
	CONVECTION REFLOW	235C	238	3	PASS	0
		TOTAL:				0
25567	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25570	TEMP CYCLE	-55C TO 125C	34	300	CYCL	0
			34	1000	CYCL	0
		TOTAL:				0
25571	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			76	959	HOUR	0
		TOTAL:				0
25572	STORAGE LIFE	150C	34	336	HOUR	0

PROJECT NO: 15310

RELIABILITY MONITOR

DS2502 JUN '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS2502	C3	0011	DM941230AGB 8	8	SOIC	150x1.4	Carsem S
PROCESS Double Poly, Single Metal 0.6 μ m EPROM process							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
			34	1000	HOUR	0
TOTAL:						0

RELIABILITY MONITOR

DS5002 JUL '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0027	DN012259AAL	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25826	INFANT LIFE	125C, 6.0 VOLTS	198	48	HOUR	0
25827	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	76	1000	HOUR	0
		TOTAL:	83	FAIL RATE (Fits): DEVICE HRS: 1.10E+07		0
25823	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25824	STORAGE LIFE	125C	203	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	0
	VAPOR PHASE REFLOW	217C	203	3	PASS	0
		TOTAL:				0
25825	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
25828	TEMP CYCLE	-55C TO 125C	37	300	CYCL	0
			37	1000	CYCL	0
		TOTAL:				0
25829	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
		TOTAL:				0
25830	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16260

RELIABILITY MONITOR

DS5002 JUL '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0027	DN012259AAL	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
--------	----------	-----------	----------	-----------	-------	-------------

RELIABILITY MONITOR

DS5002 OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0033	DN022328AAJ	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26059	INFANT LIFE	125C, 6.0 VOLTS	195	48	HOUR	0
26060	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
		125C, 6.0 VOLTS	77	1000	HOUR	0
		TOTAL:	83	FAIL RATE (Fits): DEVICE HRS: 1.11E+07		0
26056	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
26057	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	
	VAPOR PHASE REFLOW	217C	203	3	PASS	
		TOTAL:				
26058	PRECONDITION U/S	J-STD-020	4			0
		TOTAL:				0
26061	TEMP CYCLE	-55C TO 125C	38	300	CYCL	0
			38	1000	CYCL	0
		TOTAL:				0
26062	BIASED MOISTURE	85/85, 5.5 VOLTS	42	274	HOUR	0
		TOTAL:				0
26063	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16482

RELIABILITY MONITOR

DS5002 OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0033	DN022328AAJ	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μ m Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β :	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
--------	----------	-----------	----------	-----------	-------	-------------

RELIABILITY MONITOR

DS5002 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS5002	C5	0047	DN028766AAD	80	MQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Single Metal 0.6 μm Buried contacts w/silicided poly							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26508	INFANT LIFE	125C, 6.0 VOLTS	198	48	HOUR	
TOTAL:				FAIL RATE (Fits):		DEVICE HRS:
26505	ULTRASOUND	J-STD-020	4			0
TOTAL:						0
26506	STORAGE LIFE	125C	203	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	203	144	HOUR	
	VAPOR PHASE REFLOW	217C	203	3	PASS	0
TOTAL:						0
26507	PRECONDITION U/S	J-STD-020	4			0
TOTAL:						0

PROJECT NO: 16727

RELIABILITY MONITOR

DS80C320 OCT '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	0038	DH026369ABA	40	PDIP	600	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.6 μm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: Tuse:
 Ea: Vuse:
 β:

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26064	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
26065	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	DEVICE HRS: 3.08E+07		0
26066	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
			40	1000	CYCL	0
		TOTAL:				0
26067	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
			77	959	HOUR	0
		TOTAL:				0
26068	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	37	96	HOUR	0
		TOTAL:				0

PROJECT NO: 16483

RELIABILITY MONITOR

DS80C320 JAN '01 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80C320	C5	0049	DH031585BAA	40	PDIP	600	CPS (ChipPac, China)
PROCESS Single Poly, Single Metal 0.6 μm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf: <input style="width: 50px;" type="text" value="60%"/>	Tuse: <input style="width: 50px;" type="text" value="55 °C"/>
Ea: <input style="width: 50px;" type="text" value="0.7"/>	Vuse: <input style="width: 50px;" type="text" value="5.5 Volts"/>
β: <input style="width: 50px;" type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26455	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
26456	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
TOTAL:			71	DEVICE HRS: 1.29E+07		0
26457	TEMP CYCLE	-55C TO 125C	40	300	CYCL	0
TOTAL:						0
26458	BIASED MOISTURE	85/85, 5.5 VOLTS	77	274	HOUR	0
TOTAL:						0
26459	AUTOCLAVE	121C, 2 ATM STEAM, UNBIASED	38	96	HOUR	0
TOTAL:						0

PROJECT NO: 16726

RELIABILITY MONITOR

DS80CH11 DEC '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS80CH11	A4	0033	DN022359AAA	128	LQFP	14x20x	ATK (Anam, K)
PROCESS Single Poly, Double Metal 0.6 μm PolySilicide							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26398	INFANT LIFE	125C, 6.0 VOLTS	235	48	HOUR	0
26399	HIGH VOLTAGE LIFE	125C, 6.0 VOLTS	77	336	HOUR	0
TOTAL:			FAIL RATE (Fits): 635	DEVICE HRS: 1.44E+06		0
26396	STORAGE LIFE	125C	239	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	0
	CONVECTION REFLOW	235C	239	3	PASS	0
TOTAL:						0

PROJECT NO: 16681

RELIABILITY MONITOR

DS87C520 AUG '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A15	0027	DE013425AAD	44	PLCC	650x65	OSEP
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
25866	INFANT LIFE	125C, 7.0 VOLTS	234	48	HOUR	0
25867	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
		TOTAL:	30	FAIL RATE (Fits): DEVICE HRS: 3.08E+07		0
25863	ULTRASOUND	J-STD-020	4			0
		TOTAL:				0
25864	STORAGE LIFE	125C	239	24	HOUR	0
	MOISTURE SOAK	30C/60% R.H.	239	240	HOUR	0
	VAPOR PHASE REFLOW	217C	239	3	PASS	0
		TOTAL:				0
25868	TEMP CYCLE	-55C TO 125C	50	300	CYCL	0
			50	1000	CYCL	0
		TOTAL:				0
25869	HAST	130C, 85%R.H.,5.5V	57	100	HOUR	0
		TOTAL:				0
25870	STORAGE LIFE	150C	50	336	HOUR	0
			50	1000	HOUR	0
		TOTAL:				0

PROJECT NO: 16259

RELIABILITY MONITOR

DS87C520 NOV '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A15	0042	DE029195AAB	44	PLCC	650x65	OSEP
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: <input type="text" value="60%"/>	Tuse: <input type="text" value="55 °C"/>
Ea: <input type="text" value="0.7"/>	Vuse: <input type="text" value="5.5 Volts"/>
β: <input type="text" value="1"/>	

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
26200	INFANT LIFE	125C, 7.0 VOLTS	231	48	HOUR	1
26201	HIGH VOLTAGE LIFE	125C, 7.0 VOLTS	77	336	HOUR	0
		125C, 7.0 VOLTS	77	1000	HOUR	0
TOTAL:			66	DEVICE HRS: 3.08E+07		1
26198	STORAGE LIFE	125C	236	24	HOUR	
	MOISTURE SOAK	30C/60% R.H.	236	240	HOUR	
	VAPOR PHASE REFLOW	217C	236	3	PASS	0
TOTAL:						0
26202	TEMP CYCLE	-55C TO 125C	45	300	CYCL	0
			45	1000	CYCL	0
TOTAL:						0
26203	HAST	130C, 85%R.H.,5.5V	60	100	HOUR	0
TOTAL:						0
26204	STORAGE LIFE	150C	48	336	HOUR	0
			48	1000	HOUR	0
TOTAL:						0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
26200	STOP MODE	GATE OXIDE.	SEVERAL EVALUATIONS ARE IN PROCESS TO IMPROVE GATE OXIDE

PROJECT NO: 16520

RELIABILITY MONITOR

DS87C520 NOV '00 MONITOR

DEVICE	REVISION	DATE CD	LOT NUMBER	PINS	PACKAGE	WIDTH	ASSEMBLY SITE
DS87C520	A15	0042	DE029195AAB	44	PLCC	650x65	OSEP
PROCESS Double Poly, Single Metal 0.8 μm EPROM w/silicided poly(s)							

Summary Data with Chi-Square Distribution Assumed.
 Stress Ambient Temperature and Voltage to
 Field Ambient Temperature And Voltage

Cf:	<input type="text" value="60%"/>	Tuse:	<input type="text" value="55 °C"/>
Ea:	<input type="text" value="0.7"/>	Vuse:	<input type="text" value="5.5 Volts"/>
β:	<input type="text" value="1"/>		

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
PERFORMANCE						